Large area curved silicon modules for future trackers

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Abstract

 For many years there has been an aspiration within the community to develop curved silicon detectors for particle physics applications. We present the results from 10 × 10cm low mass support modules as a part of the "ZeroMass" project that aims to minimise the material budget for tracking and vertexing systems for future colliders. We use 50 µm thick DC coupled strip sensors from 11 arge radii vertex detectors. The material budget obtained varies from an X₀ of 0.05% in the active area to 0.62% in the support structure, with an average of 0.28%. There is further scope for material budget reduction in applying the concept and methods to large instruments for future detector systems, which we also discuss.
Keywords: curved silicon, tracker
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tooling, by design, increases the placement precision, but introduces other challenges, including complexity, to the assembly process.

One of the aims of this project was to understand how sensor performance changed when stress was introduced. We observe an increase in dark current when we curve the silicon to form modules. This increase is typically a few nA, and does not affect our ability to use the sensors to measure α radiation from a ²⁴¹Am source. The change in dark current (factor of 2 increase) between a flat and curved sensor is not accompanied by

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²https://www.micronsemiconductor.co.uk/product/ttt10/

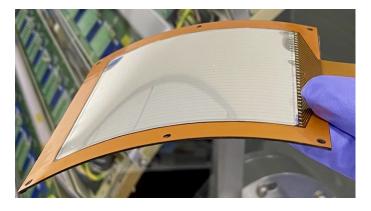


Figure 1: A curved silicon module constructed from a TTT10 sensor. The CFRP support frame overlaps with the edge of the chip by 2mm.

a change in capacitance, and as a result we conclude that this is a piezoresistance effect. See for example [4].

We use strain guages to calibrate the characteristic response curve for this effect. This enables us to determine the expected change in dark current as a function of the radius of curvature, shown in Figure 2. This indicates dark currents of a few tens of nA would be generated for radii down to a few cm.

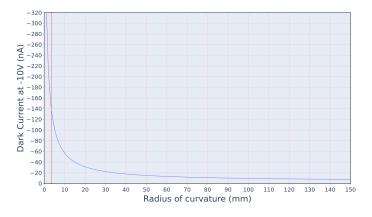


Figure 2: The predicted dark current as a function of radius of curvature for one of our TTT10 sensors used in a curved module. The vertical line indicates the physical limit of 4mm bending radius calculated for the Griffith criterion.

5. Sensor response

The response of strips in a curved sensor to α radiation from a ²⁴¹Am radiation is shown in Fig. 3. The figure shows the response of 3 adjacent strips that are read out with Cremat CR110 amplifiers³ feeding into a Tektronix MSO44 oscilloscope. The shaping time of the amplifier is 140 μ s, giving the characteristic fall off observed. The bias voltage used to collect this data is 5V, and the amplifiers were powered using a 9V supply.



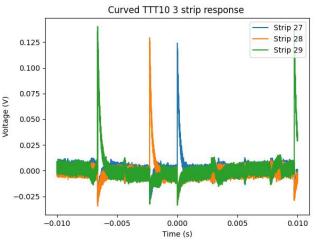


Figure 3: The response of 3 adjacent strips in the curved sensor module to α radiation.

6. Summary and future work

This work demonstrates that it is possible to make large area cylindrically curved modules. The motivation of this work using strip sensors was to study the effect of bending on the signal response. We have demonstrated it is possible to understand piezoresistance induced changes. We have identified industrial challenges that may benefit from this work, specifically radioactive waste characterisation. We are now working with industry partners on this problem, which will enable us to explore the validity of the extrapolation in Fig. 2. We are reverting to CMOS and have been working with 50 μ m thick ATLASpix3.1 chips in order to develop the work using CMOS.

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